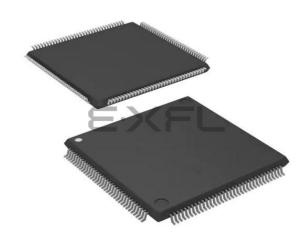
E ·) C Fart ce Semiconductor Corporation - <u>LCMXO2-4000HC-5TG144C Datasheet</u>



Welcome to E-XFL.COM

Understanding <u>Embedded - FPGAs (Field</u> <u>Programmable Gate Array)</u>

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Active
Number of LABs/CLBs	540
Number of Logic Elements/Cells	4320
Total RAM Bits	94208
Number of I/O	114
Number of Gates	-
Voltage - Supply	2.375V ~ 3.465V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	144-LQFP
Supplier Device Package	144-TQFP (20x20)
Purchase URL	https://www.e-xfl.com/product-detail/lattice-semiconductor/lcmxo2-4000hc-5tg144c

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong



MachXO2 Family Data Sheet Introduction

May 2016

Features

- Flexible Logic Architecture
 - Six devices with 256 to 6864 LUT4s and 18 to 334 I/Os
- Ultra Low Power Devices
 - Advanced 65 nm low power process
 - As low as 22 μ W standby power
 - Programmable low swing differential I/Os
 - · Stand-by mode and other power saving options

Embedded and Distributed Memory

- Up to 240 kbits sysMEM™ Embedded Block RAM
- Up to 54 kbits Distributed RAM
- Dedicated FIFO control logic
- On-Chip User Flash Memory
 - Up to 256 kbits of User Flash Memory
 - 100,000 write cycles
 - Accessible through WISHBONE, SPI, I²C and JTAG interfaces
 - Can be used as soft processor PROM or as Flash memory

Pre-Engineered Source Synchronous I/O

- DDR registers in I/O cells
- Dedicated gearing logic
- 7:1 Gearing for Display I/Os
- Generic DDR, DDRX2, DDRX4
- Dedicated DDR/DDR2/LPDDR memory with DQS support

■ High Performance, Flexible I/O Buffer

- Programmable syslO[™] buffer supports wide range of interfaces:
 - LVCMOS 3.3/2.5/1.8/1.5/1.2
 - LVTTL
 - PCI
 - LVDS, Bus-LVDS, MLVDS, RSDS, LVPECL
 - SSTL 25/18
 - HSTL 18
 - Schmitt trigger inputs, up to 0.5 V hysteresis
- I/Os support hot socketing
- On-chip differential termination
- · Programmable pull-up or pull-down mode

- Flexible On-Chip Clocking
 - · Eight primary clocks
 - Up to two edge clocks for high-speed I/O interfaces (top and bottom sides only)
 - Up to two analog PLLs per device with fractional-n frequency synthesis
 - Wide input frequency range (7 MHz to 400 MHz)

Data Sheet DS1035

- Non-volatile, Infinitely Reconfigurable
 - Instant-on powers up in microseconds
 - Single-chip, secure solution
 - Programmable through JTAG, SPI or I²C
 - Supports background programming of non-volatile memory
 - Optional dual boot with external SPI memory
- TransFR[™] Reconfiguration
 - In-field logic update while system operates

Enhanced System Level Support

- On-chip hardened functions: SPI, I²C, timer/ counter
- On-chip oscillator with 5.5% accuracy
- Unique TraceID for system tracking
- One Time Programmable (OTP) mode
- Single power supply with extended operating range
- IEEE Standard 1149.1 boundary scan
- IEEE 1532 compliant in-system programming
- Broad Range of Package Options
 - TQFP, WLCSP, ucBGA, csBGA, caBGA, ftBGA, fpBGA, QFN package options
 - Small footprint package options
 As small as 2.5 mm x 2.5 mm
 - · Density migration supported
 - Advanced halogen-free packaging



MachXO2 Family Data Sheet Architecture

March 2016

Data Sheet DS1035

Architecture Overview

The MachXO2 family architecture contains an array of logic blocks surrounded by Programmable I/O (PIO). The larger logic density devices in this family have sysCLOCK[™] PLLs and blocks of sysMEM Embedded Block RAM (EBRs). Figure 2-1 and Figure 2-2 show the block diagrams of the various family members.





Note: MachXO2-256, and MachXO2-640/U are similar to MachXO2-1200. MachXO2-256 has a lower LUT count and no PLL or EBR blocks. MachXO2-640 has no PLL, a lower LUT count and two EBR blocks. MachXO2-640U has a lower LUT count, one PLL and seven EBR blocks.

Figure 2-2. Top View of the MachXO2-4000 Device



Note: MachXO2-1200U, MachXO2-2000/U and MachXO2-7000 are similar to MachXO2-4000. MachXO2-1200U and MachXO2-2000 have a lower LUT count, one PLL, and eight EBR blocks. MachXO2-2000U has a lower LUT count, two PLLs, and 10 EBR blocks. MachXO2-7000 has a higher LUT count, two PLLs, and 26 EBR blocks.

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This phase shift can be either programmed during configuration or can be adjusted dynamically. In dynamic mode, the PLL may lose lock after a phase adjustment on the output used as the feedback source and not relock until the $t_{I,OCK}$ parameter has been satisfied.

The MachXO2 also has a feature that allows the user to select between two different reference clock sources dynamically. This feature is implemented using the PLLREFCS primitive. The timing parameters for the PLL are shown in the sysCLOCK PLL Timing table.

The MachXO2 PLL contains a WISHBONE port feature that allows the PLL settings, including divider values, to be dynamically changed from the user logic. When using this feature the EFB block must also be instantiated in the design to allow access to the WISHBONE ports. Similar to the dynamic phase adjustment, when PLL settings are updated through the WISHBONE port the PLL may lose lock and not relock until the t_{LOCK} parameter has been satisfied. The timing parameters for the PLL are shown in the sysCLOCK PLL Timing table.

For more details on the PLL and the WISHBONE interface, see TN1199, MachXO2 sysCLOCK PLL Design and Usage Guide.



Figure 2-7. PLL Diagram

Table 2-4 provides signal descriptions of the PLL block.

Table 2-4. PLL Signal	Descriptions
-----------------------	--------------

Port Name	I/O	Description
CLKI	I	Input clock to PLL
CLKFB	I	Feedback clock
PHASESEL[1:0]	I	Select which output is affected by Dynamic Phase adjustment ports
PHASEDIR	I	Dynamic Phase adjustment direction
PHASESTEP	I	Dynamic Phase step – toggle shifts VCO phase adjust by one step.



Table 2-4. PLL Signal Descriptions (Continued)

Port Name	I/O	Description
CLKOP	0	Primary PLL output clock (with phase shift adjustment)
CLKOS	0	Secondary PLL output clock (with phase shift adjust)
CLKOS2	0	Secondary PLL output clock2 (with phase shift adjust)
CLKOS3	0	Secondary PLL output clock3 (with phase shift adjust)
LOCK	0	PLL LOCK, asynchronous signal. Active high indicates PLL is locked to input and feed- back signals.
DPHSRC	0	Dynamic Phase source – ports or WISHBONE is active
STDBY	I	Standby signal to power down the PLL
RST	I	PLL reset without resetting the M-divider. Active high reset.
RESETM	I	PLL reset - includes resetting the M-divider. Active high reset.
RESETC	I	Reset for CLKOS2 output divider only. Active high reset.
RESETD	I	Reset for CLKOS3 output divider only. Active high reset.
ENCLKOP	I	Enable PLL output CLKOP
ENCLKOS	I	Enable PLL output CLKOS when port is active
ENCLKOS2	I	Enable PLL output CLKOS2 when port is active
ENCLKOS3	I	Enable PLL output CLKOS3 when port is active
PLLCLK	I	PLL data bus clock input signal
PLLRST	I	PLL data bus reset. This resets only the data bus not any register values.
PLLSTB	I	PLL data bus strobe signal
PLLWE	I	PLL data bus write enable signal
PLLADDR [4:0]	I	PLL data bus address
PLLDATI [7:0]	ļ	PLL data bus data input
PLLDATO [7:0]	0	PLL data bus data output
PLLACK	0	PLL data bus acknowledge signal

sysMEM Embedded Block RAM Memory

The MachXO2-640/U and larger devices contain sysMEM Embedded Block RAMs (EBRs). The EBR consists of a 9-kbit RAM, with dedicated input and output registers. This memory can be used for a wide variety of purposes including data buffering, PROM for the soft processor and FIFO.

sysMEM Memory Block

The sysMEM block can implement single port, dual port, pseudo dual port, or FIFO memories. Each block can be used in a variety of depths and widths as shown in Table 2-5.



Figure 2-11. Group of Four Programmable I/O Cells



Notes:

1. Input gearbox is available only in PIC on the bottom edge of MachXO2-640U, MachXO2-1200/U and larger devices. 2. Output gearbox is available only in PIC on the top edge of MachXO2-640U, MachXO2-1200/U and larger devices.







Tri-state Register Block

The tri-state register block registers tri-state control signals from the core of the device before they are passed to the sysIO buffers. The block contains a register for SDR operation. In SDR, TD input feeds one of the flip-flops that then feeds the output.

The tri-state register blocks on the right edge contain an additional register for DDR memory operation. In DDR memory mode, the register TS input is fed into another register that is clocked using the DQSW90 signal. The output of this register is used as a tri-state control.

Input Gearbox

Each PIC on the bottom edge has a built-in 1:8 input gearbox. Each of these input gearboxes may be programmed as a 1:7 de-serializer or as one IDDRX4 (1:8) gearbox or as two IDDRX2 (1:4) gearboxes. Table 2-9 shows the gearbox signals.

Name	I/O Type	Description
D	Input	High-speed data input after programmable delay in PIO A input register block
ALIGNWD	Input	Data alignment signal from device core
SCLK	Input	Slow-speed system clock
ECLK[1:0]	Input	High-speed edge clock
RST	Input	Reset
Q[7:0]	Output	Low-speed data to device core: Video RX(1:7): Q[6:0] GDDRX4(1:8): Q[7:0] GDDRX2(1:4)(IOL-A): Q4, Q5, Q6, Q7 GDDRX2(1:4)(IOL-C): Q0, Q1, Q2, Q3



MachXO2-640U, MachXO2-1200/U, MachXO2-2000/U, MachXO2-4000 and MachXO2-7000 devices contain three types of sysIO buffer pairs.

1. Left and Right sysIO Buffer Pairs

The sysIO buffer pairs in the left and right banks of the device consist of two single-ended output drivers and two single-ended input buffers (for ratioed inputs such as LVCMOS and LVTTL). The I/O pairs on the left and right of the devices also have differential and referenced input buffers.

2. Bottom sysIO Buffer Pairs

The sysIO buffer pairs in the bottom bank of the device consist of two single-ended output drivers and two single-ended input buffers (for ratioed inputs such as LVCMOS and LVTTL). The I/O pairs on the bottom also have differential and referenced input buffers. Only the I/Os on the bottom banks have programmable PCI clamps and differential input termination. The PCI clamp is enabled after V_{CC} and V_{CCIO} are at valid operating levels and the device has been configured.

3. Top sysIO Buffer Pairs

The sysIO buffer pairs in the top bank of the device consist of two single-ended output drivers and two singleended input buffers (for ratioed inputs such as LVCMOS and LVTTL). The I/O pairs on the top also have differential and referenced I/O buffers. Half of the sysIO buffer pairs on the top edge have true differential outputs. The sysIO buffer pair comprising of the A and B PIOs in every PIC on the top edge have a differential output driver. The referenced input buffer can also be configured as a differential input buffer.

Typical I/O Behavior During Power-up

The internal power-on-reset (POR) signal is deactivated when V_{CC} and V_{CCIO0} have reached V_{PORUP} level defined in the Power-On-Reset Voltage table in the DC and Switching Characteristics section of this data sheet. After the POR signal is deactivated, the FPGA core logic becomes active. It is the user's responsibility to ensure that all V_{CCIO} banks are active with valid input logic levels to properly control the output logic states of all the I/O banks that are critical to the application. The default configuration of the I/O pins in a blank device is tri-state with a weak pulldown to GND (some pins such as PROGRAMN and the JTAG pins have weak pull-up to V_{CCIO} as the default functionality). The I/O pins will maintain the blank configuration until V_{CC} and V_{CCIO} (for I/O banks containing configuration I/Os) have reached V_{PORUP} levels at which time the I/Os will take on the user-configured settings only after a proper download/configuration.

Supported Standards

The MachXO2 sysIO buffer supports both single-ended and differential standards. Single-ended standards can be further subdivided into LVCMOS, LVTTL, and PCI. The buffer supports the LVTTL, PCI, LVCMOS 1.2, 1.5, 1.8, 2.5, and 3.3 V standards. In the LVCMOS and LVTTL modes, the buffer has individually configurable options for drive strength, bus maintenance (weak pull-up, weak pull-down, bus-keeper latch or none) and open drain. BLVDS, MLVDS and LVPECL output emulation is supported on all devices. The MachXO2-640U, MachXO2-1200/U and higher devices support on-chip LVDS output buffers on approximately 50% of the I/Os on the top bank. Differential receivers for LVDS, BLVDS, MLVDS and LVPECL are supported on all banks of MachXO2 devices. PCI support is provided in the bottom bank of theMachXO2-640U, MachXO2-1200/U and higher density devices. Table 2-11 summarizes the I/O characteristics of the MachXO2 PLDs.

Tables 2-11 and 2-12 show the I/O standards (together with their supply and reference voltages) supported by the MachXO2 devices. For further information on utilizing the sysIO buffer to support a variety of standards please see TN1202, MachXO2 sysIO Usage Guide.



Configuration and Testing

This section describes the configuration and testing features of the MachXO2 family.

IEEE 1149.1-Compliant Boundary Scan Testability

All MachXO2 devices have boundary scan cells that are accessed through an IEEE 1149.1 compliant test access port (TAP). This allows functional testing of the circuit board, on which the device is mounted, through a serial scan path that can access all critical logic nodes. Internal registers are linked internally, allowing test data to be shifted in and loaded directly onto test nodes, or test data to be captured and shifted out for verification. The test access port consists of dedicated I/Os: TDI, TDO, TCK and TMS. The test access port shares its power supply with V_{CCIO} Bank 0 and can operate with LVCMOS3.3, 2.5, 1.8, 1.5, and 1.2 standards.

For more details on boundary scan test, see AN8066, Boundary Scan Testability with Lattice sysIO Capability and TN1087, Minimizing System Interruption During Configuration Using TransFR Technology.

Device Configuration

All MachXO2 devices contain two ports that can be used for device configuration. The Test Access Port (TAP), which supports bit-wide configuration and the sysCONFIG port which supports serial configuration through I²C or SPI. The TAP supports both the IEEE Standard 1149.1 Boundary Scan specification and the IEEE Standard 1532 In-System Configuration specification. There are various ways to configure a MachXO2 device:

- 1. Internal Flash Download
- 2. JTAG
- 3. Standard Serial Peripheral Interface (Master SPI mode) interface to boot PROM memory
- 4. System microprocessor to drive a serial slave SPI port (SSPI mode)
- 5. Standard I²C Interface to system microprocessor

Upon power-up, the configuration SRAM is ready to be configured using the selected sysCONFIG port. Once a configuration port is selected, it will remain active throughout that configuration cycle. The IEEE 1149.1 port can be activated any time after power-up by sending the appropriate command through the TAP port. Optionally the device can run a CRC check upon entering the user mode. This will ensure that the device was configured correctly.

The sysCONFIG port has 10 dual-function pins which can be used as general purpose I/Os if they are not required for configuration. See TN1204, MachXO2 Programming and Configuration Usage Guide for more information about using the dual-use pins as general purpose I/Os.

Lattice design software uses proprietary compression technology to compress bit-streams for use in MachXO2 devices. Use of this technology allows Lattice to provide a lower cost solution. In the unlikely event that this technology is unable to compress bitstreams to fit into the amount of on-chip Flash memory, there are a variety of techniques that can be utilized to allow the bitstream to fit in the on-chip Flash memory. For more details, refer to TN1204, MachXO2 Programming and Configuration Usage Guide.

The Test Access Port (TAP) has five dual purpose pins (TDI, TDO, TMS, TCK and JTAGENB). These pins are dual function pins - TDI, TDO, TMS and TCK can be used as general purpose I/O if desired. For more details, refer to TN1204, MachXO2 Programming and Configuration Usage Guide.

TransFR (Transparent Field Reconfiguration)

TransFR is a unique Lattice technology that allows users to update their logic in the field without interrupting system operation using a simple push-button solution. For more details refer to TN1087, Minimizing System Interruption During Configuration Using TransFR Technology for details.



Static Supply Current – HC/HE Devices^{1, 2, 3, 6}

Symbol	Parameter	Device	Typ.⁴	Units
		LCMXO2-256HC	1.15	mA
		LCMXO2-640HC	1.84	mA
		LCMXO2-640UHC	3.48	mA
		LCMXO2-1200HC	3.49	mA
		LCMXO2-1200UHC	4.80	mA
1	Core Power Supply	LCMXO2-2000HC	4.80	mA
ICC		LCMXO2-2000UHC	8.44	mA
		LCMXO2-4000HC	8.45	mA
		LCMXO2-7000HC	12.87	mA
		LCMXO2-2000HE	1.39	mA
		LCMXO2-4000HE	2.55	mA
		LCMXO2-7000HE	4.06	mA
Іссю	Bank Power Supply⁵ V _{CCIO} = 2.5 V	All devices	0	mA

1. For further information on supply current, please refer to TN1198, Power Estimation and Management for MachXO2 Devices.

2. Assumes blank pattern with the following characteristics: all outputs are tri-stated, all inputs are configured as LVCMOS and held at V_{CCIO} or GND, on-chip oscillator is off, on-chip PLL is off.

3. Frequency = 0 MHz.

4. $T_J = 25$ °C, power supplies at nominal voltage.

5. Does not include pull-up/pull-down.

6. To determine the MachXO2 peak start-up current data, use the Power Calculator tool.

Programming and Erase Flash Supply Current – HC/HE Devices^{1, 2, 3, 4}

Symbol	Parameter	Device	Typ.⁵	Units
		LCMXO2-256HC	14.6	mA
		LCMXO2-640HC	16.1	mA
		LCMXO2-640UHC	18.8	mA
		LCMXO2-1200HC	18.8	mA
		LCMXO2-1200UHC	22.1	mA
		LCMXO2-2000HC	22.1	mA
I _{CC}	Core Power Supply	LCMXO2-2000UHC	26.8	mA
		LCMXO2-4000HC	26.8	mA
		LCMXO2-7000HC	33.2	mA
		LCMXO2-2000HE	18.3	mA
		LCMXO2-2000UHE	20.4	mA
		LCMXO2-4000HE	20.4	mA
		LCMXO2-7000HE	23.9	mA
I _{CCIO}	Bank Power Supply ⁶	All devices	0	mA

1. For further information on supply current, please refer to TN1198, Power Estimation and Management for MachXO2 Devices.

2. Assumes all inputs are held at V_{CCIO} or GND and all outputs are tri-stated.

3. Typical user pattern.

4. JTAG programming is at 25 MHz.

5. $T_J = 25$ °C, power supplies at nominal voltage.

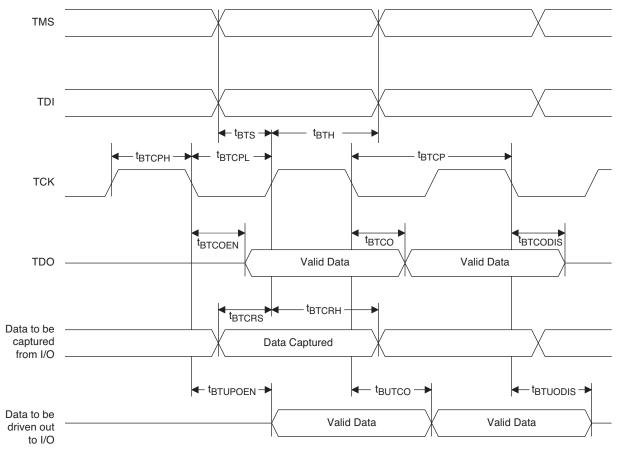
6. Per bank. $V_{CCIO} = 2.5$ V. Does not include pull-up/pull-down.



			_	3	_	2	_	1	
Parameter	Description	Device	Min.	Max.	Min.	Max.	Min.	Max.	Units
Generic DDR4	Inputs with Clock and Data Cer	ntered at Pin Using PC	LK Pin fo	or Clock	Input –	GDDRX4	RX.EC	LK.Cent	tered ^{9, 12}
t _{SU}	Input Data Setup Before ECLK		0.434	—	0.535	_	0.630	—	ns
t _{HO}	Input Data Hold After ECLK	MachXO2-640U,	0.385	—	0.395	—	0.463	—	ns
f _{DATA}	DDRX4 Serial Input Data Speed	MachXO2-1200/U and larger devices,	_	420	_	352		292	Mbps
f _{DDRX4}	DDRX4 ECLK Frequency	bottom side only ¹¹	—	210	—	176	_	146	MHz
f _{SCLK}	SCLK Frequency			53		44		37	MHz
	uts – GDDR71_RX.ECLK.7.1 ^{9, 12}	2							
t _{DVA}	Input Data Valid After ECLK		—	0.307		0.316		0.326	UI
t _{DVE}	Input Data Hold After ECLK		0.662	—	0.650		0.649		UI
f _{DATA}	DDR71 Serial Input Data Speed	MachXO2-640U, MachXO2-1200/U	_	420	_	352		292	Mbps
f _{DDR71}	DDR71 ECLK Frequency	and larger devices, bottom side only ¹¹	—	210	—	176	—	146	MHz
f _{CLKIN}	7:1 Input Clock Frequency (SCLK) (minimum limited by PLL)	bottom side only	_	60	_	50	_	42	MHz
Generic DDR	Outputs with Clock and Data A	ligned at Pin Using PC	LK Pin f	or Clock	k Input –	GDDRX	1_TX.S	CLK.Aliç	jned ^{9, 12}
t _{DIA}	Output Data Invalid After CLK Output		—	0.850	—	0.910	_	0.970	ns
t _{DIB}	Output Data Invalid Before CLK Output	All MachXO2 devices, all sides	_	0.850	_	0.910		0.970	ns
f _{DATA}	DDRX1 Output Data Speed		—	140	—	116	_	98	Mbps
f _{DDRX1}	DDRX1 SCLK frequency		—	70	—	58	_	49	MHz
	Outputs with Clock and Data Ce	ntered at Pin Using PC	LK Pin f	or Clock	Input –	GDDRX	1_TX.SC	LK.Cen	tered ^{9, 12}
t _{DVB}	Output Data Valid Before CLK Output		2.720	_	3.380		4.140		ns
t _{DVA}	Output Data Valid After CLK Output	All MachXO2	2.720		3.380	_	4.140		ns
f _{DATA}	DDRX1 Output Data Speed	devices, all sides	—	140	—	116	—	98	Mbps
f _{DDRX1}	DDRX1 SCLK Frequency (minimum limited by PLL)		_	70	_	58	_	49	MHz
Generic DDRX	(2 Outputs with Clock and Data	Aligned at Pin Using P	CLK Pin	for Cloc	k Input	- GDDR	X2_TX.E	CLK.Ali	gned ^{9, 12}
t _{DIA}	Output Data Invalid After CLK Output			0.270		0.300		0.330	ns
t _{DIB}	Output Data Invalid Before CLK Output	MachXO2-640U, MachXO2-1200/U	_	0.270	_	0.300		0.330	ns
f _{DATA}	DDRX2 Serial Output Data Speed	and larger devices, top side only	_	280	_	234		194	Mbps
f _{DDRX2}	DDRX2 ECLK frequency		_	140	—	117	_	97	MHz
f _{SCLK}	SCLK Frequency		—	70	—	59	—	49	MHz









MachXO2 Family Data Sheet Pinout Information

March 2017

Data Sheet DS1035

Signal Descriptions

Signal Name	I/O	Descriptions
General Purpose		
		[Edge] indicates the edge of the device on which the pad is located. Valid edge designations are L (Left), B (Bottom), R (Right), T (Top).
		[Row/Column Number] indicates the PFU row or the column of the device on which the PIO Group exists. When Edge is T (Top) or (Bottom), only need to specify Row Number. When Edge is L (Left) or R (Right), only need to specify Column Number.
		[A/B/C/D] indicates the PIO within the group to which the pad is connected.
P[Edge] [Row/Column Number]_[A/B/C/D]	I/O	Some of these user-programmable pins are shared with special function pins. When not used as special function pins, these pins can be programmed as I/Os for user logic.
		During configuration of the user-programmable I/Os, the user has an option to tri-state the I/Os and enable an internal pull-up, pull-down or buskeeper resistor. This option also applies to unused pins (or those not bonded to a package pin). The default during configuration is for user-programmable I/Os to be tri-stated with an internal pull-down resistor enabled. When the device is erased, I/Os will be tri-stated with an internal pull-down resistor enabled. Some pins, such as PROGRAMN and JTAG pins, default to tri-stated I/Os with pull-up resistors enabled when the device is erased.
NC	—	No connect.
GND	_	GND – Ground. Dedicated pins. It is recommended that all GNDs are tied together. For QFN 48 package, the exposed die pad is the device ground.
VCC	_	V_{CC} – The power supply pins for core logic. Dedicated pins. It is recommended that all VCCs are tied to the same supply.
VCCIOx	_	VCCIO – The power supply pins for I/O Bank x. Dedicated pins. It is recommended that all VCCIOs located in the same bank are tied to the same supply.
PLL and Clock Function	ons (Us	ed as user-programmable I/O pins when not used for PLL or clock pins)
[LOC]_GPLL[T, C]_IN	_	Reference Clock (PLL) input pads: [LOC] indicates location. Valid designations are L (Left PLL) and R (Right PLL). T = true and C = complement.
[LOC]_GPLL[T, C]_FB	_	Optional Feedback (PLL) input pads: [LOC] indicates location. Valid designations are L (Left PLL) and R (Right PLL). T = true and C = complement.
PCLK [n]_[2:0]	—	Primary Clock pads. One to three clock pads per side.
Test and Programming	g (Dual f	function pins used for test access port and during sysCONFIG™)
TMS	I	Test Mode Select input pin, used to control the 1149.1 state machine.
ТСК	I	Test Clock input pin, used to clock the 1149.1 state machine.
TDI	I	Test Data input pin, used to load data into the device using an 1149.1 state machine.
TDO	0	Output pin – Test Data output pin used to shift data out of the device using 1149.1.
		Optionally controls behavior of TDI, TDO, TMS, TCK. If the device is configured to use the JTAG pins (TDI, TDO, TMS, TCK) as general purpose I/O, then:
JTAGENB	I	If JTAGENB is low: TDI, TDO, TMS and TCK can function a general purpose I/O.
		If JTAGENB is high: TDI, TDO, TMS and TCK function as JTAG pins.
		For more details, refer to TN1204, MachXO2 Programming and Configuration Usage Guide.
Configuration (Dual fu	nction p	ins used during sysCONFIG)
PROGRAMN	I	Initiates configuration sequence when asserted low. During configuration, or when reserved as PROGRAMN in user mode, this pin always has an active pull-up.

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For Further Information

For further information regarding logic signal connections for various packages please refer to the MachXO2 Device Pinout Files.

Thermal Management

Thermal management is recommended as part of any sound FPGA design methodology. To assess the thermal characteristics of a system, Lattice specifies a maximum allowable junction temperature in all device data sheets. Users must complete a thermal analysis of their specific design to ensure that the device and package do not exceed the junction temperature limits. Refer to the Thermal Management document to find the device/package specific thermal values.

For Further Information

For further information regarding Thermal Management, refer to the following:

- Thermal Management document
- TN1198, Power Estimation and Management for MachXO2 Devices
- The Power Calculator tool is included with the Lattice design tools, or as a standalone download from www.latticesemi.com/software



MachXO2 Family Data Sheet Ordering Information

March 2017

Data Sheet DS1035

MachXO2 Part Number Description



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Ultra Low Power Commercial Grade Devices, Halogen Free (RoHS) Packaging

Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-256ZE-1SG32C	256	1.2 V	–1	Halogen-Free QFN	32	COM
LCMXO2-256ZE-2SG32C	256	1.2 V	-2	Halogen-Free QFN	32	COM
LCMXO2-256ZE-3SG32C	256	1.2 V	-3	Halogen-Free QFN	32	COM
LCMXO2-256ZE-1UMG64C	256	1.2 V	–1	Halogen-Free ucBGA	64	COM
LCMXO2-256ZE-2UMG64C	256	1.2 V	-2	Halogen-Free ucBGA	64	COM
LCMXO2-256ZE-3UMG64C	256	1.2 V	-3	Halogen-Free ucBGA	64	COM
LCMXO2-256ZE-1TG100C	256	1.2 V	-1	Halogen-Free TQFP	100	COM
LCMXO2-256ZE-2TG100C	256	1.2 V	-2	Halogen-Free TQFP	100	COM
LCMXO2-256ZE-3TG100C	256	1.2 V	-3	Halogen-Free TQFP	100	COM
LCMXO2-256ZE-1MG132C	256	1.2 V	-1	Halogen-Free csBGA	132	COM
LCMXO2-256ZE-2MG132C	256	1.2 V	-2	Halogen-Free csBGA	132	COM
LCMXO2-256ZE-3MG132C	256	1.2 V	-3	Halogen-Free csBGA	132	COM

Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-640ZE-1TG100C	640	1.2 V	-1	Halogen-Free TQFP	100	COM
LCMXO2-640ZE-2TG100C	640	1.2 V	-2	Halogen-Free TQFP	100	COM
LCMXO2-640ZE-3TG100C	640	1.2 V	-3	Halogen-Free TQFP	100	COM
LCMXO2-640ZE-1MG132C	640	1.2 V	-1	Halogen-Free csBGA	132	COM
LCMXO2-640ZE-2MG132C	640	1.2 V	-2	Halogen-Free csBGA	132	COM
LCMXO2-640ZE-3MG132C	640	1.2 V	-3	Halogen-Free csBGA	132	COM

Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-1200ZE-1SG32C	1280	1.2 V	-1	Halogen-Free QFN	32	COM
LCMXO2-1200ZE-2SG32C	1280	1.2 V	-2	Halogen-Free QFN	32	COM
LCMXO2-1200ZE-3SG32C	1280	1.2 V	-3	Halogen-Free QFN	32	COM
LCMXO2-1200ZE-1TG100C	1280	1.2 V	-1	Halogen-Free TQFP	100	COM
LCMXO2-1200ZE-2TG100C	1280	1.2 V	-2	Halogen-Free TQFP	100	COM
LCMXO2-1200ZE-3TG100C	1280	1.2 V	-3	Halogen-Free TQFP	100	COM
LCMXO2-1200ZE-1MG132C	1280	1.2 V	-1	Halogen-Free csBGA	132	COM
LCMXO2-1200ZE-2MG132C	1280	1.2 V	-2	Halogen-Free csBGA	132	COM
LCMXO2-1200ZE-3MG132C	1280	1.2 V	-3	Halogen-Free csBGA	132	COM
LCMXO2-1200ZE-1TG144C	1280	1.2 V	-1	Halogen-Free TQFP	144	COM
LCMXO2-1200ZE-2TG144C	1280	1.2 V	-2	Halogen-Free TQFP	144	COM
LCMXO2-1200ZE-3TG144C	1280	1.2 V	-3	Halogen-Free TQFP	144	COM



Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-2000ZE-1TG100C	2112	1.2 V	-1	Halogen-Free TQFP	100	COM
LCMXO2-2000ZE-2TG100C	2112	1.2 V	-2	Halogen-Free TQFP	100	COM
LCMXO2-2000ZE-3TG100C	2112	1.2 V	-3	Halogen-Free TQFP	100	COM
LCMXO2-2000ZE-1MG132C	2112	1.2 V	-1	Halogen-Free csBGA	132	COM
LCMXO2-2000ZE-2MG132C	2112	1.2 V	-2	Halogen-Free csBGA	132	COM
LCMXO2-2000ZE-3MG132C	2112	1.2 V	-3	Halogen-Free csBGA	132	COM
LCMXO2-2000ZE-1TG144C	2112	1.2 V	-1	Halogen-Free TQFP	144	COM
LCMXO2-2000ZE-2TG144C	2112	1.2 V	-2	Halogen-Free TQFP	144	COM
LCMXO2-2000ZE-3TG144C	2112	1.2 V	-3	Halogen-Free TQFP	144	COM
LCMXO2-2000ZE-1BG256C	2112	1.2 V	-1	Halogen-Free caBGA	256	COM
LCMXO2-2000ZE-2BG256C	2112	1.2 V	-2	Halogen-Free caBGA	256	COM
LCMXO2-2000ZE-3BG256C	2112	1.2 V	-3	Halogen-Free caBGA	256	COM
LCMXO2-2000ZE-1FTG256C	2112	1.2 V	-1	Halogen-Free ftBGA	256	COM
LCMXO2-2000ZE-2FTG256C	2112	1.2 V	-2	Halogen-Free ftBGA	256	COM
LCMXO2-2000ZE-3FTG256C	2112	1.2 V	-3	Halogen-Free ftBGA	256	COM

Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-4000ZE-1QN84C	4320	1.2 V	-1	Halogen-Free QFN	84	COM
LCMXO2-4000ZE-2QN84C	4320	1.2 V	-2	Halogen-Free QFN	84	COM
LCMXO2-4000ZE-3QN84C	4320	1.2 V	-3	Halogen-Free QFN	84	COM
LCMXO2-4000ZE-1MG132C	4320	1.2 V	-1	Halogen-Free csBGA	132	COM
LCMXO2-4000ZE-2MG132C	4320	1.2 V	-2	Halogen-Free csBGA	132	COM
LCMXO2-4000ZE-3MG132C	4320	1.2 V	-3	Halogen-Free csBGA	132	COM
LCMXO2-4000ZE-1TG144C	4320	1.2 V	-1	Halogen-Free TQFP	144	COM
LCMXO2-4000ZE-2TG144C	4320	1.2 V	-2	Halogen-Free TQFP	144	COM
LCMXO2-4000ZE-3TG144C	4320	1.2 V	-3	Halogen-Free TQFP	144	COM
LCMXO2-4000ZE-1BG256C	4320	1.2 V	-1	Halogen-Free caBGA	256	COM
LCMXO2-4000ZE-2BG256C	4320	1.2 V	-2	Halogen-Free caBGA	256	COM
LCMXO2-4000ZE-3BG256C	4320	1.2 V	-3	Halogen-Free caBGA	256	COM
LCMXO2-4000ZE-1FTG256C	4320	1.2 V	-1	Halogen-Free ftBGA	256	COM
LCMXO2-4000ZE-2FTG256C	4320	1.2 V	-2	Halogen-Free ftBGA	256	COM
LCMXO2-4000ZE-3FTG256C	4320	1.2 V	-3	Halogen-Free ftBGA	256	COM
LCMXO2-4000ZE-1BG332C	4320	1.2 V	-1	Halogen-Free caBGA	332	COM
LCMXO2-4000ZE-2BG332C	4320	1.2 V	-2	Halogen-Free caBGA	332	COM
LCMXO2-4000ZE-3BG332C	4320	1.2 V	-3	Halogen-Free caBGA	332	COM
LCMXO2-4000ZE-1FG484C	4320	1.2 V	-1	Halogen-Free fpBGA	484	COM
LCMXO2-4000ZE-2FG484C	4320	1.2 V	-2	Halogen-Free fpBGA	484	COM
LCMXO2-4000ZE-3FG484C	4320	1.2 V	-3	Halogen-Free fpBGA	484	COM



R1 Device Specifications

The LCMXO2-1200ZE/HC "R1" devices have the same specifications as their Standard (non-R1) counterparts except as listed below. For more details on the R1 to Standard migration refer to AN8086, Designing for Migration from MachXO2-1200-R1 to Standard Non-R1) Devices.

- The User Flash Memory (UFM) cannot be programmed through the internal WISHBONE interface. It can still be programmed through the JTAG/SPI/I²C ports.
- The on-chip differential input termination resistor value is higher than intended. It is approximately 200Ω as opposed to the intended 100Ω. It is recommended to use external termination resistors for differential inputs. The on-chip termination resistors can be disabled through Lattice design software.
- Soft Error Detection logic may not produce the correct result when it is run for the first time after configuration. To use this feature, discard the result from the first operation. Subsequent operations will produce the correct result.
- Under certain conditions, IIH exceeds data sheet specifications. The following table provides more details:

Condition	Clamp	Pad Rising IIH Max.	Pad Falling IIH Min.	Steady State Pad High IIH	Steady State Pad Low IIL
VPAD > VCCIO	OFF	1 mA	–1 mA	1 mA	10 µA
VPAD = VCCIO	ON	10 µA	–10 μA	10 µA	10 µA
VPAD = VCCIO	OFF	1 mA	–1 mA	1 mA	10 µA
VPAD < VCCIO	OFF	10 µA	–10 μA	10 µA	10 µA

- The user SPI interface does not operate correctly in some situations. During master read access and slave write access, the last byte received does not generate the RRDY interrupt.
- In GDDRX2, GDDRX4 and GDDR71 modes, ECLKSYNC may have a glitch in the output under certain conditions, leading to possible loss of synchronization.
- When using the hard I²C IP core, the I²C status registers I2C_1_SR and I2C_2_SR may not update correctly.
- PLL Lock signal will glitch high when coming out of standby. This glitch lasts for about 10 μsec before returning low.
- Dual boot only available on HC devices, requires tying VCC and VCCIO2 to the same 3.3 V or 2.5 V supply.



MachXO2 Family Data Sheet Supplemental Information

April 2012

Data Sheet DS1035

For Further Information

A variety of technical notes for the MachXO2 family are available on the Lattice web site.

- TN1198, Power Estimation and Management for MachXO2 Devices
- TN1199, MachXO2 sysCLOCK PLL Design and Usage Guide
- TN1201, Memory Usage Guide for MachXO2 Devices
- TN1202, MachXO2 sysIO Usage Guide
- TN1203, Implementing High-Speed Interfaces with MachXO2 Devices
- TN1204, MachXO2 Programming and Configuration Usage Guide
- TN1205, Using User Flash Memory and Hardened Control Functions in MachXO2 Devices
- TN1206, MachXO2 SRAM CRC Error Detection Usage Guide
- TN1207, Using TraceID in MachXO2 Devices
- TN1074, PCB Layout Recommendations for BGA Packages
- TN1087, Minimizing System Interruption During Configuration Using TransFR Technology
- AN8086, Designing for Migration from MachXO2-1200-R1 to Standard (non-R1) Devices
- AN8066, Boundary Scan Testability with Lattice sysIO Capability
- MachXO2 Device Pinout Files
- Thermal Management document
- · Lattice design tools

For further information on interface standards, refer to the following web sites:

- JEDEC Standards (LVTTL, LVCMOS, LVDS, DDR, DDR2, LPDDR): www.jedec.org
- PCI: www.pcisig.com

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Image: space with the second secon	Date	Version	Section	Change Summary
Guide table. Architecture Added information to Standby Mode and Power Saving Options section. Pinout Information Added the XO2-2000 49 WLCSP in the Pinout Information Summary table. Ordering Information Added the XO2-2000 2E in the Pinout Information Summary table. Ordering Information Added the XO2-2000ZE-1UWG49CTR in Ultra Low Power Commercial Grade Devices, Halogen Free (RoHS) Packaging section. Added and LCMXO2-2000ZE-1UWG49ITR in Ultra Low Power Industrial Grade Devices, Halogen Free (RoHS) Packaging section. Added and LCMXO2-2000ZE-1UWG49ITR in Ultra Low Power Industrial Grade Devices, Halogen Free (RoHS) Packaging section. December 2013 02.3 Architecture Updated Information on CLKOS output divider in sysCLOCK Phase Locked Loops (PLLs) section. DC and Switching Updated footnote 4 in sysIO Single-Ended DC Electrical Characteristics table; Updated V _{IL} Max. (V) data for LVCMOS 25 and LVCMOS 28. Updated V _{OS} test condition in sysIO Differential Electrical Characteristics - LVDS table. Updated Supported Input Standards table. DC and Switching Updated Power-On-Reset Voltage Levels table. Updated Supported Input Standards table. June 2013 02.1 Architecture Architecture Overview – Added information on the state of the register on power up and after configuration. June 2013 02.1 Architecture Architec	May 2014	2.5	Architecture	Updated TransFR description for PLL use during background Flash
Image: section of the sectio	February 2014	02.4	Introduction	
Image: series of the series			Architecture	
Added and LCMXO2-2000ZE-1UWG49CTR in Ultra Low Power Commercial Grade Devices, Halogen Free (RoHS) Packaging section. Added and LCMXO2-2000ZE-1UWG49ITR in Ultra Low Power Industrial Grade Devices, Halogen Free (RoHS) Packaging section. December 2013 02.3 Architecture Updated information on CLKOS output divider in sysCLOCK Phase Locked Loops (PLLs) section. DC and Switching Characteristics Updated Static Supply Current – ZE Devices table. Updated footnote 4 in sysIO Single-Ended DC Electrical Characteris tics table; Updated V _{IL} Max. (V) data for LVCMOS 25 and LVCMOS 28. Updated Vos test condition in sysIO Differential Electrical Characteri- istics - LVDS table. September 2013 02.2 Oz and Switching Characteristics Removed I ² C Clock-Stretching feature per PCN #10A-13. Removed information on PDPR memory in RAM Mode section. Updated Supported Input Standards table. June 2013 02.1 Architecture Architecture Overview – Added information on the state of the regis- ter on power up and after configuration. sysCLOCK Phase Locked Loops (PLLs) section – Added missing cross reference to sysCLOC KPLL Timing table. Added slew rate information to footnote 2 of the MachXO2 External Switching Characteristics – HC/HE Devices and the MachXO2 External Switching Characteristics – ZE Devices tables.			Pinout Information	Added the XO2-2000 49 WLCSP in the Pinout Information Summary table.
Image: bit is a series of the serie			Ordering Information	Added UW49 package in MachXO2 Part Number Description.
Industrial Grade Devices, Halogen Free (RoHS) Packaging section. December 2013 02.3 Architecture Updated information on CLKOS output divider in sysCLOCK Phase Locked Loops (PLLs) section. DC and Switching Characteristics Updated Static Supply Current – ZE Devices table. Updated footnote 4 in sysIO Single-Ended DC Electrical Characteris tics table; Updated V _{IL} Max. (V) data for LVCMOS 25 and LVCMOS 28. September 2013 02.2 Architecture Removed I ² C Clock-Stretching feature per PCN #10A-13. Removed I ² C Clock-Stretching feature per PCN #10A-13. Removed information on PDPR memory in RAM Mode section. Updated Supported Input Standards table. Updated Power-On-Reset Voltage Levels table. June 2013 02.1 Architecture Architecture Overview – Added information on the state of the register on power up and after configuration. SysCLOCK Phase Locked Loops (PLLs) section – Added missing cross reference to sysCLOCK PLL Timing table. DC and Switching Characteristics Added slew rate information to footnote 2 of the MachXO2 External Switching Characteristics – ED Povices and the MachXO2 External Switching Characteristics – ZE Devices tables.				Commercial Grade Devices, Halogen Free (RoHS) Packaging sec-
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Updated Supported Input Standards table. DC and Switching Characteristics Updated Power-On-Reset Voltage Levels table. June 2013 02.1 Architecture Architecture Overview – Added information on the state of the register on power up and after configuration. SysCLOCK Phase Locked Loops (PLLs) section – Added missing cross reference to sysCLOCK PLL Timing table. DC and Switching Characteristics Added slew rate information to footnote 2 of the MachXO2 External Switching Characteristics – HC/HE Devices and the MachXO2 External Switching Characteristics – ZE Devices tables.	September 2013	02.2	Architecture	Removed I ² C Clock-Stretching feature per PCN #10A-13.
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Characteristics Switching Characteristics – HC/HE Devices and the MachXO2 External Switching Characteristics – ZE Devices tables.				
Power-On-Reset Voltage Levels table – Added symbols.				Switching Characteristics - HC/HE Devices and the MachXO2 Exter-
				Power-On-Reset Voltage Levels table – Added symbols.



Date	Version	Section	Change Summary
May 2011	01.3	Multiple	Replaced "SED" with "SRAM CRC Error Detection" throughout the document.
		DC and Switching Characteristics	Added footnote 1 to Program Erase Specifications table.
		Pinout Information	Updated Pin Information Summary tables.
			Signal name SO/SISPISO changed to SO/SPISO in the Signal Descriptions table.
April 2011	01.2	_	Data sheet status changed from Advance to Preliminary.
		Introduction	Updated MachXO2 Family Selection Guide table.
		Architecture	Updated Supported Input Standards table.
			Updated sysMEM Memory Primitives diagram.
			Added differential SSTL and HSTL IO standards.
		DC and Switching Characteristics	Updates following parameters: POR voltage levels, DC electrical characteristics, static supply current for ZE/HE/HC devices, static power consumption contribution of different components – ZE devices, programming and erase Flash supply current.
			Added VREF specifications to sysIO recommended operating condi- tions.
			Updating timing information based on characterization.
			Added differential SSTL and HSTL IO standards.
		Ordering Information	Added Ordering Part Numbers for R1 devices, and devices in WLCSP packages.
			Added R1 device specifications.
January 2011	01.1	All	Included ultra-high I/O devices.
		DC and Switching Characteristics	Recommended Operating Conditions table – Added footnote 3.
			DC Electrical Characteristics table – Updated data for $\rm I_{IL}, I_{IH}, V_{HYST}$ typical values updated.
			Generic DDRX2 Outputs with Clock and Data Aligned at Pin (GDDRX2_TX.ECLK.Aligned) Using PCLK Pin for Clock Input tables – Updated data for T_{DIA} and T_{DIB} .
			Generic DDRX4 Outputs with Clock and Data Aligned at Pin (GDDRX4_TX.ECLK.Aligned) Using PCLK Pin for Clock Input tables – Updated data for T_{DIA} and T_{DIB} .
			Power-On-Reset Voltage Levels table - clarified note 3.
			Clarified VCCIO related recommended operating conditions specifications.
			Added power supply ramp rate requirements.
			Added Power Supply Ramp Rates table.
			Updated Programming/Erase Specifications table.
			Removed references to V _{CCP.}
		Pinout Information	Included number of 7:1 and 8:1 gearboxes (input and output) in the pin information summary tables.
			Removed references to V _{CCP.}
November 2010	01.0	—	Initial release.